

**Search Notes**

Application/Control No.

10/601,815

Examiner

Christian A. Hannon

Applicant(s)/Patent under  
Reexamination

ECKL ET AL.

Art Unit

2618

**SEARCHED**

Class	Subclass	Date	Examiner
331	177V	5/2/06	CH
455	180.4	5/2/06	CH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Consulted w/ Q. Vuong	5/2/06	CH